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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/682,054	10/09/2003	Kim Hwee Tan	APS03-002	8182
STEPHEN B. A	7590 . 06/13/2007 ACKERMAN		EXAMINER PHAM, THANH V	
28 DAVIS AV	ENUE		PHAM, T	HANH V .
POUGHKEEPS	SIE, NY 12603		ART UNIT	PAPER NUMBER
	•		2823	
			MAIL DATE	DELIVERY MODE
			06/13/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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	Application No.	Applicant(s)	, , ,
	10/682,054	TAN ET AL.	
Office Action Summary	Examiner	Art Unit	
	Thanh V. Pham	2823	
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with th	e correspondence address	••
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING D Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATI 36(a). In no event, however, may a reply be will apply and will expire SIX (6) MONTHS for e, cause the application to become ABANDO	ON. e timely filed from the mailing date of this communication ONED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed on <u>02 M</u>	lay 2007.		
2a)⊠ This action is FINAL . 2b)☐ This	s action is non-final.		
3) Since this application is in condition for alloward closed in accordance with the practice under E		•	s is
Disposition of Claims			
 4) Claim(s) 1-13,16,19-35,38,41-58,61 and 64-77 4a) Of the above claim(s) is/are withdray 5) Claim(s) is/are allowed. 6) Claim(s) 1-13, 16, 19-35, 38, 41-58, 61 and 64 7) Claim(s) is/are objected to. 	wn from consideration.	on.	
8) Claim(s) are subject to restriction and/o	r election requirement.		
Application Papers 9)☐ The specification is objected to by the Examine	ar.		
10) The drawing(s) filed on is/are: a) acc		ne Examiner.	•
Applicant may not request that any objection to the			_
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Ex	tion is required if the drawing(s) is	objected to. See 37 CFR 1.12	
Priority under 35 U.S.C. § 119	×.		
 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Burea 	ts have been received. ts have been received in Applic rity documents have been rece u (PCT Rule 17.2(a)).	cation No eived in this National Stage)
* See the attached detailed Office action for a list	of the certified copies not rece	ived.	
Attachment(s) 1) \(\sum \) Notice of References Cited (PTO-892)	4) Interview Summ	ary (PTO-413)	
2) Notice of Preferences Cried (170-032) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date	Paper No(s)/Ma 5) Notice of Inform 6) Other:	il Date	

DETAILED ACTION

Response to Amendment

Claim Objections

1. Claim 1 is objected to because of the following informalities: "in a pattern" on line 4 should be --in patterns-- to match with "two or more" on line 3; and "are" on line 5 should be --is-- to match with "at least one" on line 4.

In the same manner, claim 46 is objected to as "in a pattern" on line 4 should be in patterns-- to match with "two or more" on line 3.

Appropriate correction is required.

Claim Rejections - 35 USC § 102

2. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.

Claims 1-2, 9, 11-13, 19 and 24, 31, 33-35, 41 and 46-47, 54, 56-58, 64 and 69-71 are rejected under 35 U.S.C. 102(b) as being anticipated by Kondoh et al. US 5,448,114 (provided by applicant).

Re claims 1 and 46, the Kondoh et al. reference discloses a die comprising: (providing) a substrate 1; and

(forming) two or more different type of pillar structures 3 and 4 formed over the substrate 1 in patterns (figs. 1-4, e.g.);

at least one of the two or more different types of pillar structures is bi-layer having a lower *high-melting-point non-solder* portion 53 and an upper *solder-material* portion 54 over and in substantial contact with only an upper surface of the lower *high-*

melting-point non-solder portion 53 (fig. 11); wherein the lower high-melting-point non-solder portion 53 does not melt during a reflow process to form the two or more different types of pillar structures.

Re claims 2, 24 and 47, wherein at least one of the two or more different types of pillar structures has a rectangular shape, a round shape, a ring shape, a wall-like shape or a spline shape (figs. 2 or 7, a side of element 3 or the square shape of element 4 is considered as a special rectangular with the two consecutive equal sides; or round shape, col. 10, lines 57-58, e.g.).

Re claims 9, 31 and 54, the pillar structure pattern includes 2 rows and 2 columns, fig. 2.

Re claims 11-13, 33-35 and 56-58, the one pillar structure 3 is wall-shaped pillar structure forming a square, fig. 2.

Re claims 19, 41 and 64, a lower copper layer 53 and an overlying reflowed solder layer 54, the solder layer being comprised of 60 % tin and 40 % lead (col. 14, lines 16-33).

Re claims 69-71, the lower lead-free portion 53 is comprised of copper (col. 14, lines 26 and 52).

Claim Rejections - 35 USC § 103

- 3. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.
- 4. Claims 3-8, 10, 16, 20-23 and 25-30, 32, 38, 42-45 and 48-53, 55, 61, 65-68 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kondoh et al. as applied to

Application/Control Number: 10/682,054

Art Unit: 2823

claims 1-2, 9, 11-13, 19 and 24, 31, 33-35, 41 and 46-47, 54, 56-58, 64 and 69-71 above, and further in view of Lee et al. US 6,642,136 B1 and the following reasons.

The Kondoh et al. reference discloses substantially all of the invention. Although it discloses "the bump 4 is approximately 100 micron square and 50 micron high, and the wall member 3 is approximately 300 micron wide and 50 micron high" (col. 9, lines 40-42), "the size of the chip is approximately 6 mm square and the number of pads is approximately 40. Therefore, the contact area of the bump is approximately 0.4 mm² and that of the wall is approximately 4.0 mm²" (col. 10, lines 3-7, e.g.); it does not disclose the length, width, height and distance apart of each of the bumps nor the diameter of the sound pillar structure as claimed in claims 3-8, 10, 21-22 and 25-30, 32, 43-44 and 48-53, 55, 66-67. However, one of ordinary skill in the art would have been led to the recited dimensions through routine experimentation to achieve desired device dimensions and associated device properties and desired device density on the finished wafer. Applicant has not disclosed that the dimensions are for a particular unobvious purpose, produce an unexpected result, or are otherwise critical, and it appears prima facie that the process would possess utility using another dimension. Indeed, it has been held that mere dimensional limitations are prima facie obvious absent a disclosure that the limitations are for a particular unobvious purpose, produce an unexpected result, or are otherwise critical. See, for example, In re Rose, 220 F.2d 459, 105 USPQ 237 (CCPA 1955); In re Rinehart, 531 F.2d 1048, 189 USPQ 143 (CCPA 1976); Gardner v. TEC Systems, Inc., 725 F.2d 1338, 220 USPQ 777 (Fed. Cir. 1984), cert. denied, 469 U.S. 830, 225 USPQ 232

(1984); In re Dailey, 357 F.2d 669, 149 USPQ 47 (CCPA 1966). See also MPEP 2144.04(IV)(B).

Re claims 16, 38 and 61, the Kondoh et al. reference discloses (col. 14, line 52) "barrier layer 53 made of nickel, copper, or palladium". The Lee et al. reference discloses a lower lead free portion 54 of a solder bump made of copper coated with nickel 56 and covered with solder 58 (fig. 8). It would have been obvious to one of ordinary skill in the art at the time of the invention to provide the lower lead-free portion of copper coated with nickel of Lee et al. because the structure and method of Lee et al. would provide the structure and method of Kondoh with "high-pillar solder bump that sustains a high stand-off of the complete solder bump while maintaining high bump reliability and minimizing damage caused by mismatching or thermal stress factors between the interfacing surface" (Lee et al.'s col. 2, lines 19-23).

Re claims 20, 42 and 65, the Kondoh et al. reference discloses the solder layer being comprised of 60 % tin and 40 % lead (col. 14, lines 28-29), "combination of the first supporting layer and second supporting layer is not restricted to the above combination" (col. 15, lines 1-6). Choice of the solder layer being consisting of about 63 % tin and 37 % lead or 100 % tin would have been a matter of routine optimization because the ratio of material in a layer are known to affect device properties and would depend on the desired device density on the finished wafer and the desired device characteristics. One of ordinary skill in the art would have been led to the recited ratio through routine experimentation to achieve desired deposition and reaction rates.

Application/Control Number: 10/682,054 Page 6

Art Unit: 2823

Re claims 23, 45 and 68, the Kondoh et al. reference discloses "when the semiconductor device is a high frequency element, using the electrode 7 as a ground line provides a shielding effect" or "since the active area is isolated from the outside world by the chip itself, circuit board, and wall member, especially when the semiconductor device is a high-frequency element, the electrical shielding effect can be expected", col. 9, lines 27-29 and lines 50-53. Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to use the shield of Kondoh et al. in Surface Acoustic Wave device and in MEM device because the shield would proved the Surface Acoustic Wave device or MEM device with proper shielding effect as taught by Kondoh et al.

Response to Arguments

- 5. Applicant's arguments with respect to all claims have been considered but are most in view of the new ground(s) of rejection.
- 6. Note: In response to applicant's argument on the materials of elements 3 and 4, applicant is directed to Kondoh et al.'s col. 10, lines 55-65, col. 12, lines 4-22 and col. 14 for Kondoh et al.'s explanation of "reflow" condition of formed materials wherein the claimed structure is held in between the two reflows.

Conclusion

- 7. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- 8. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP

§ 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thanh V. Pham whose telephone number is 571-272-1866. The examiner can normally be reached on M-T (6:30-5:00).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on 571-272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/682,054 Page 8

Art Unit: 2823

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

06/05/2007

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